

Built-In-Self Test for Embedded Memories by Finite State Machine

Swati Singh
singh06swatigmail.com

Dr. UBS Chandrawat
uday22bana@yahoo.co.in

Abstract – In today's Integrated Circuits (IC's) designs Built-in Self-Test (BIST) is becoming important for the memory which is the most necessary part of the System on Chip. The March algorithm has been widely used to test memory core of System on chip (SOC). This paper describes the FSM based programmable BIST which is improved method as compared to previous method in terms of area (having lower gate counts). This technique is useful both for engineering debug as well as for product testing.

Keywords – IC, BIST, SOC.

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